

Surface Roughness and Scatter Measurement Instrumentation

Surface Measurements on Reflectance and BRDF Roughness (Ra, RMS or P-V) Measurements in Angstroms, or Micro-inches



µScan Control Unit, Measurement Head and cable

Applications

- **Optical surfaces**
- Semiconductor wafers

Features

- Microprocessor controlled
- Interchangeable measurement heads
- RS232 serial port
- Rechargeable battery or external power
- PC compatible software

System Description

The SMS µScan System consists of a hand held Control Unit (CU), an interchangeable measurement head, and a separate charging unit. The CU controls all aspects of the system operation.

To perform a measurement, the operator places the measurement head on the surface to be measured and presses the button. Each measurement takes less than five seconds.

The results are clearly displayed and stored in system memory. The µScan can store 700 measurements in 255 files and provides the capability to program pass/fail criteria. Software is available for control, analysis and file conversion.

SMS, the leader in light scatter measurement technology, is proud to announce our portable surface measurement instrument, the SMS µScan System.

The SMS µScan System allows the operator to rapidly take measurements at the sample - where you need them - in seconds. From a single measurement, a user can determine RMS surface roughness, reflectance and scattered light level (BRDF) on flat or curved surfaces under any lighting conditions.

- Precision machined surfaces
- Rolled & formed surfaces

Benefits

- Surface roughness/reflectance
- Scatter characterization (BRDF)
- Accommodates flat or curved surfaces
- Nondestructive
- Adaptable for in-process control
- Retrievable data storage for future analysis

µScan® Technical Information





Measurement Head

Measurements

Range:	(Ra, RMS, P-V) (Reflectance) (BRDF)	From 1Å up to 1100Å From 0.1 up to 100.0% From 1 ^{e-6} to 1 ^{e0} (sr ⁻¹)	.01 to 5 µin.
Spatial Bandwidth:	Upper Lower	10 to 999 μm (selectable) 1.0 μm	

Measurement Head

Dimensions Weight Time of Measurement Spot Size	5"h x 3½"d 1¼ lbs. < 5 seconds 1 mm				
Repeatability	±0.5%				
Accuracy	±2% Reflectance				
	±3% Scatter				
Wavelength	670nm (1300nm available)				
1.Laser diode					
2.Reflectance detector and specular beam trap					

- 3.Scatter detectors

Control Unit

Dimenions			1¾"h x 4½"wx9½"d		Storage	
Weight Power Source Batteri - Type - Dura - Char		2 lbs. Rechargeable NiCd > 5 hours Turbo < 3 hours.	·	ature Coefficient Scatter detectors Reflectance dete atile Memory	ector	±0.1%per °C ±0.15%per °C
Extern	al	trickle 15 hours 9 VDC to 11 VDC		Storage capacity Number of files Real Time Clock		700 measurements 255
Data Transfer Temperature Ra Opera	4800, 2 (no par nge	ate selectable to 9600, 2400, 1200, 300 bps ity, 8 bits, 1 stop bit) -10C to + 45C (LCD Limited)	Display	Size Lighting Contrast Control	LED ba	20 character LCD cklit controllable
Charger						
Dimension Weight Power		4½"hx4¾"wx8½"d 3¼ lbs. 110 VAC, 50/60 HZ (100∖	VAC and 220	VAC, 50/60 HZ Avai	lable)	
P.C. Software						
Functions		Downloads files to PC for process control limits. For format. Provides PC cont	rmats data an			
System Requirer	ments	One (1) 1.44Meg -3½" fle 100% PC/AT Compatible 512K available memory		d hard drive.		
	*	CAUTIO	DN	Schmitt Mea 2765 NW Nic Portland, Or Phone: (503)	colai St. egon 9	7210

P.C.





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